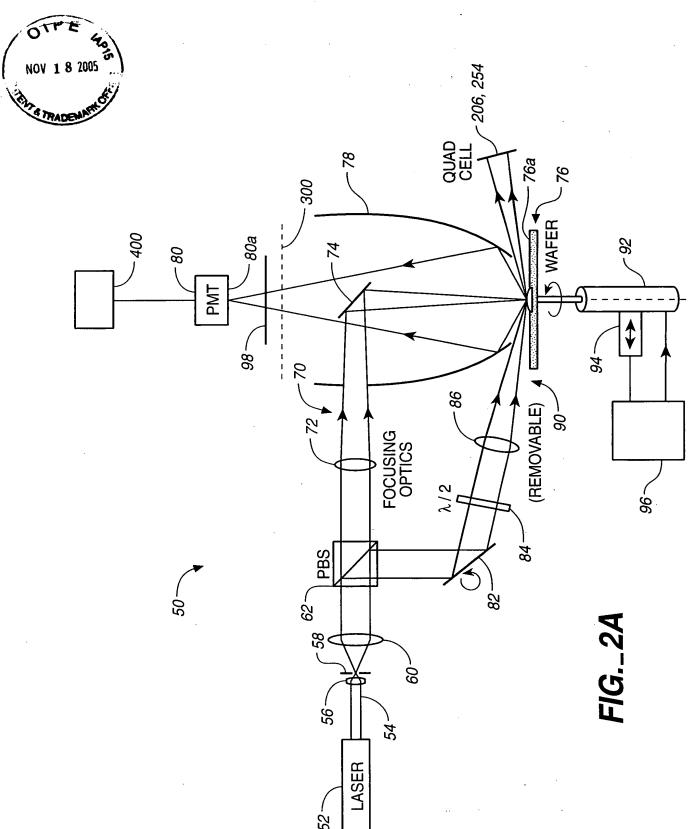


Appln. No. 10/627,402 Filing Date: July 24, 2003
Title: Sample Inspection System
Inventors: Mehdi Vaez-Iravani et al.
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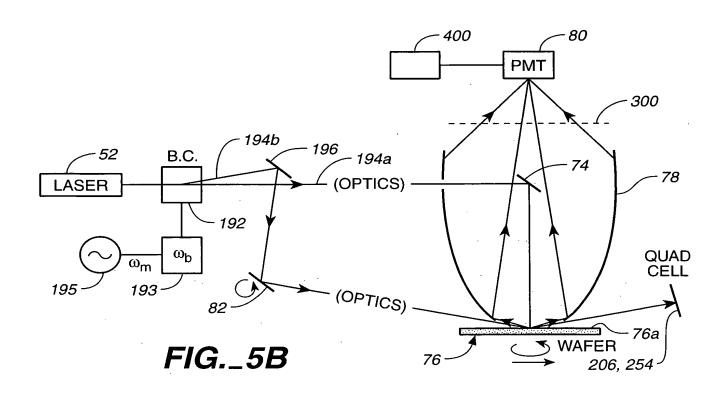


Appln. No. 10/627,402 Filing Date: July 24, 2003
Title: Sample Inspection System
Inventors: Mehdi Vaez-Iravani et al.
Atty Docket: TNCR.152US7 REPLACEMENT SHEET 3 OF 8 Filing Date: July 24, 2003 206, 254 QUAD 78, -300 102 WAFER WAFER 80a - 80 - 104 PMT 186 98 (REMOVABLE) -06 FOCUSING OPTICS 70 $\lambda/2$ 72 84-PBS 82 100 - 58 62-99 -95 54-LASER

Appln. No. 10/627,402 Fi Title: Sample Inspection System Inventors: Mehdi Vaez-Iravani et al. Atty Docket: TNCR.152US7 REP! Filing Date: July 24, 2003 REPLACEMENT SHEET 4 OF 8 DICHROIC BEAM SPLITTER -166 76a 300 - PINHOLE -80(1) 168 - 74 \mathcal{F} PMT -86 170-90'λ₁ FOCUSING OPTICS کی PMT 82 DICHROIC BEAM SPLITTER 162~ 26 λ1,λ2 54" LASER

Appln. No. 10/627,402 Fi Title: Sample Inspection System Inventors: Mehdi Vaez-Iravani et al. Atty Docket: TNCR.152US7 REP Filing Date: July 24, 2003 REPLACEMENT SHEET 5 OF 8 400 80 180 **PMT** *300* E.O. 52 **PBS** 74 78 (OPTICS) .ASER 62 54 182 QUAD CELL 184 (OPTICS) 82 76a **WAFER**

FIG._5A



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206, 254

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NOV 18 2005

N

76a

h

WAFER

76a'

h

WAFER

76a'

FIG._6

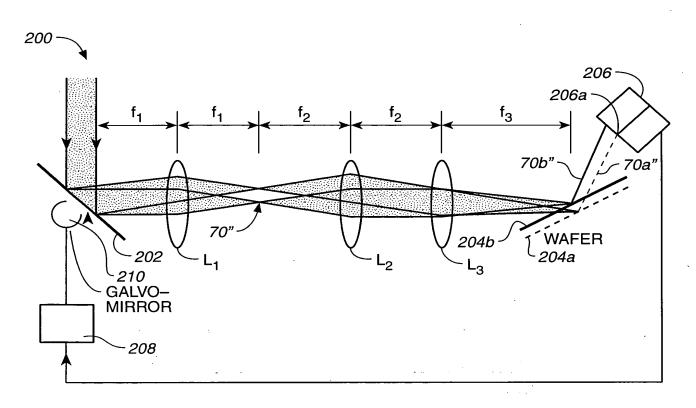
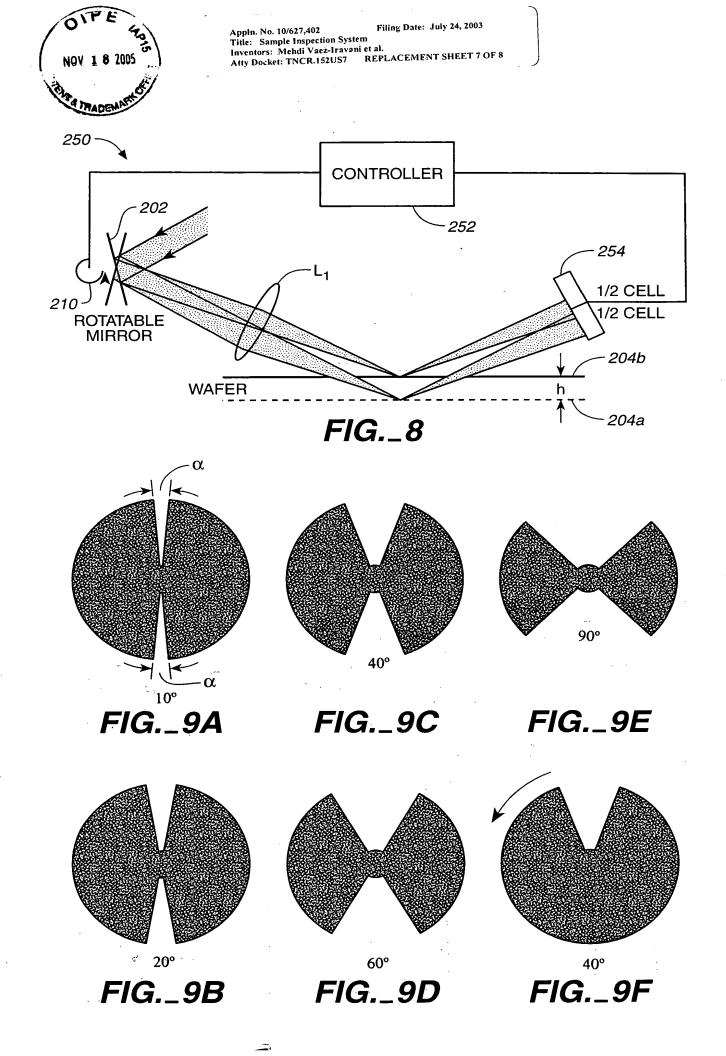


FIG._7





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FIG._10A

